

Test beam studies for passive CMOS strip sensor

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9th Beam Telescopes and Test Beam
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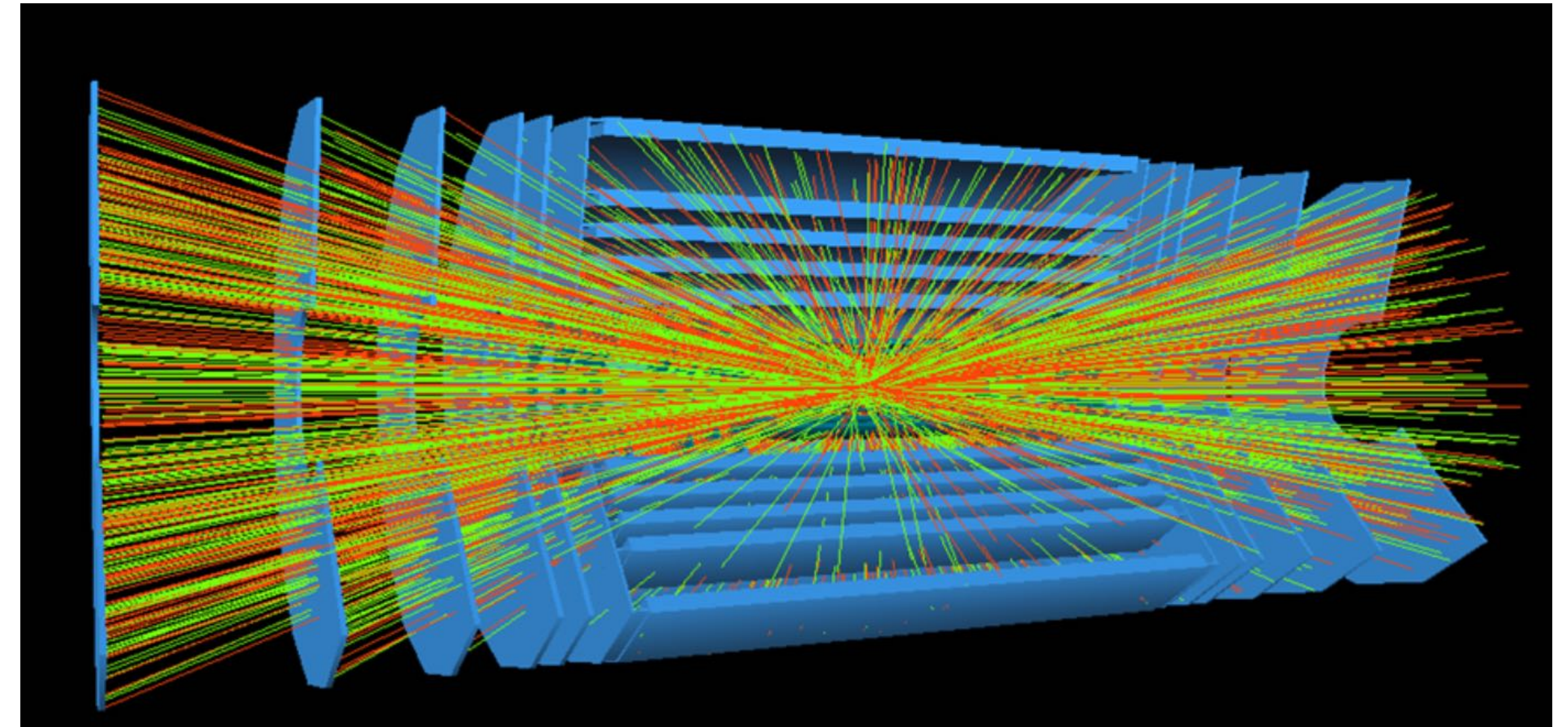


Outline

- **Sensor Details**
- **Electrical measurement**
- **Goals and Setup for Test beam**
- **ALiBaVa setup**
- **Analysis Strategy**
- **ALiBaVa data reconstruction**
- **Telescope data reconstruction**

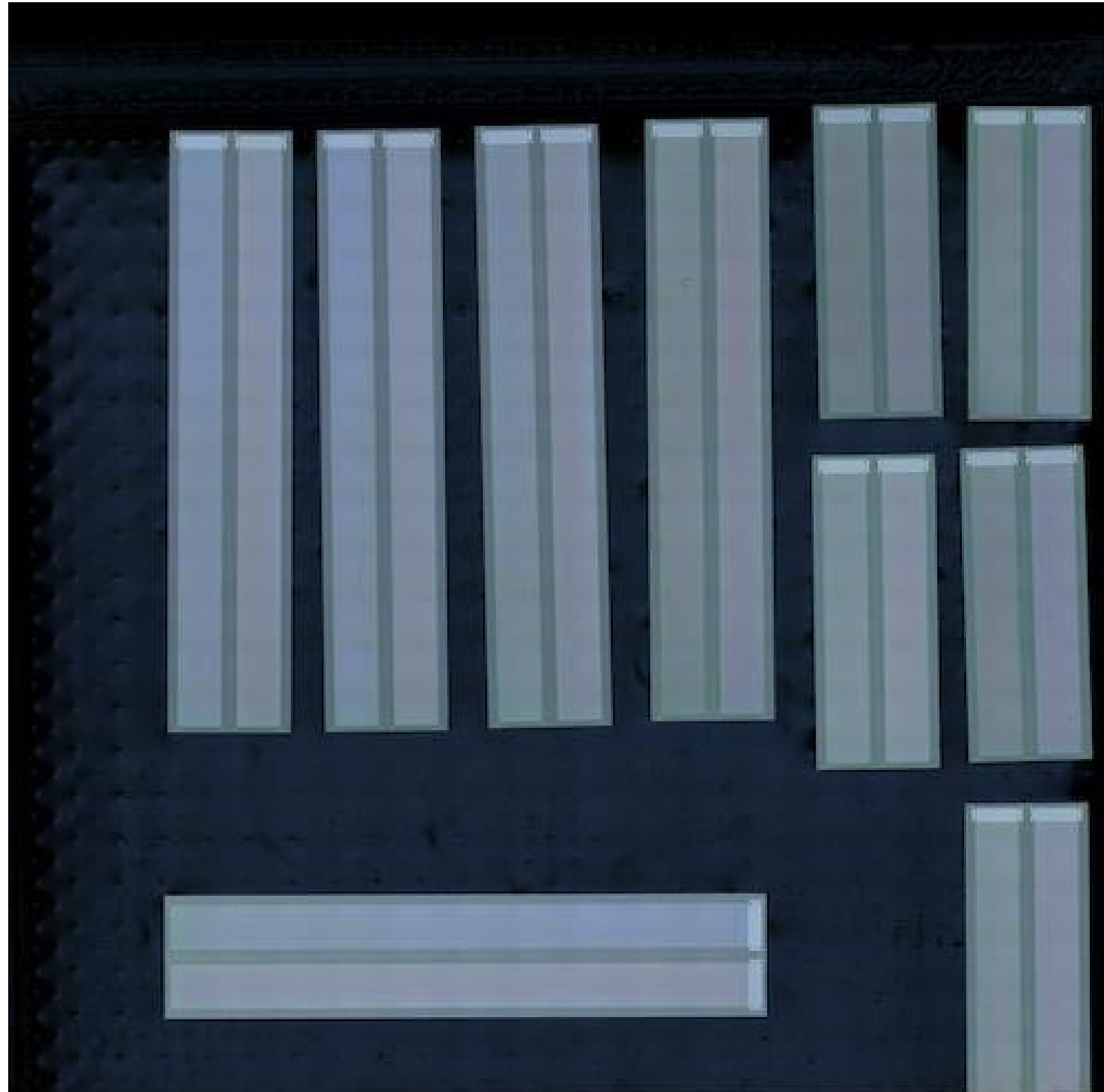
Motivation for passive CMOS

- **Requirements for future HEP detectors**
 - All silicon-based tracker
 - Possibly more radiation tolerant
 - Large surface
 - Cost effective-> Use of commercial CMOS production process



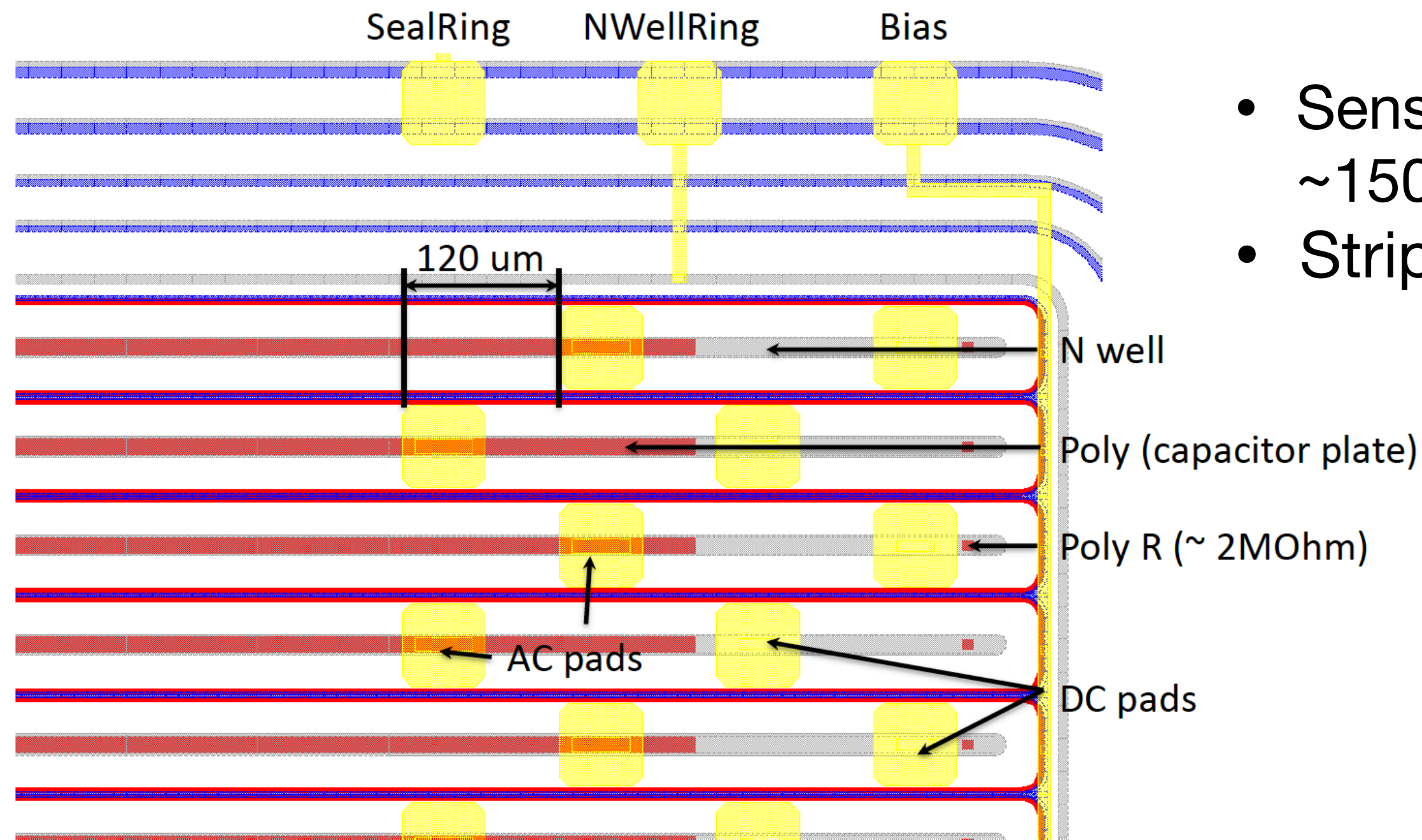
ATLAS detector in HL-LHC

Sensor structure



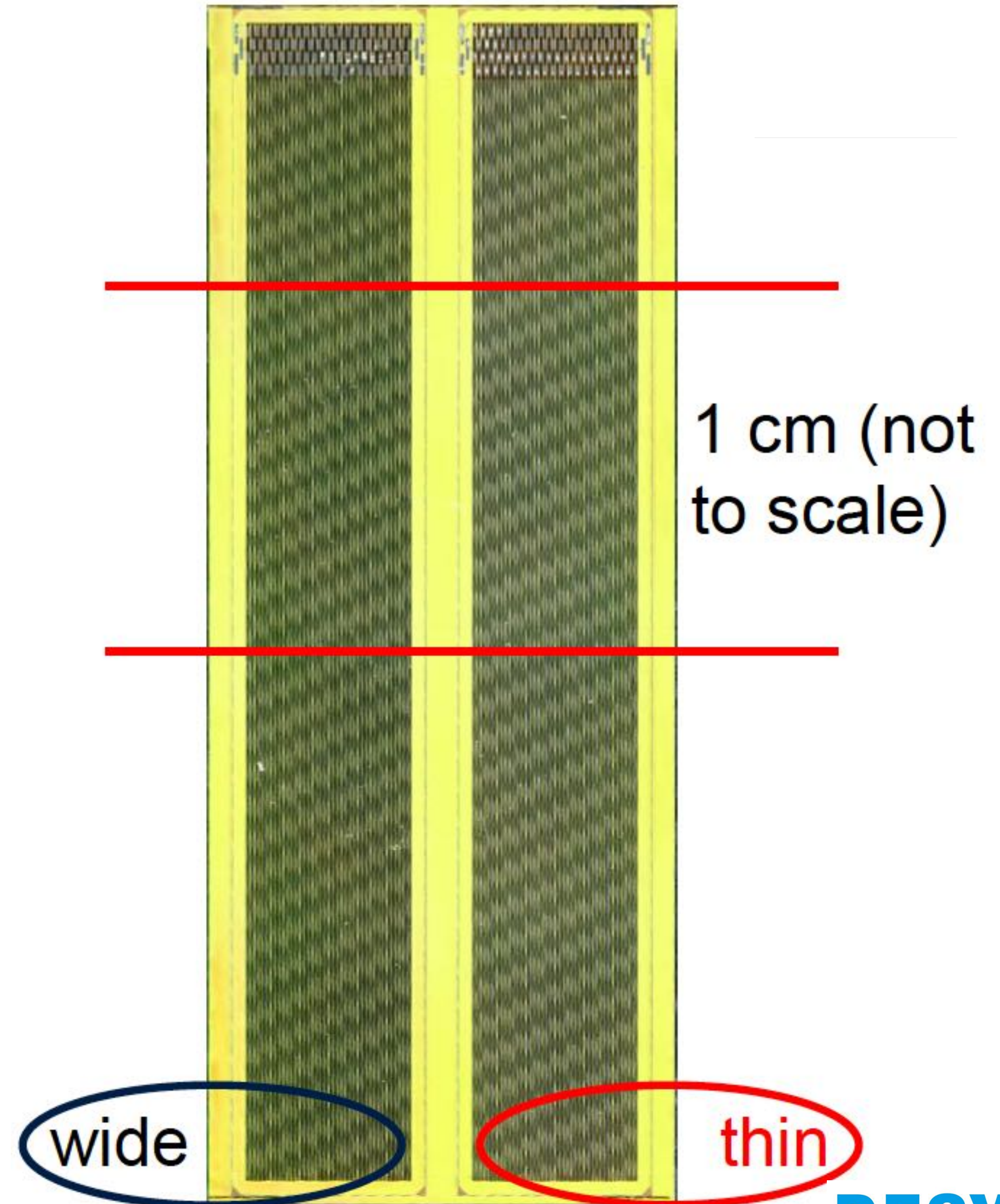
- First stitched strip sensor produced on 8" wafer by a commercial foundry
- **LFA150:**
 - L-Foundry 150 nm process (deep N-well/P-well)
 - Up to 7 metal layers
 - Resistivity of wafer: $>2000 \Omega \cdot \text{cm}$
 - Float-zone processing
- Frontside process: Reticle stitching for large sensors
- The strip sensors has 2 different lengths : 2 cm and 4 cm

Sensor details



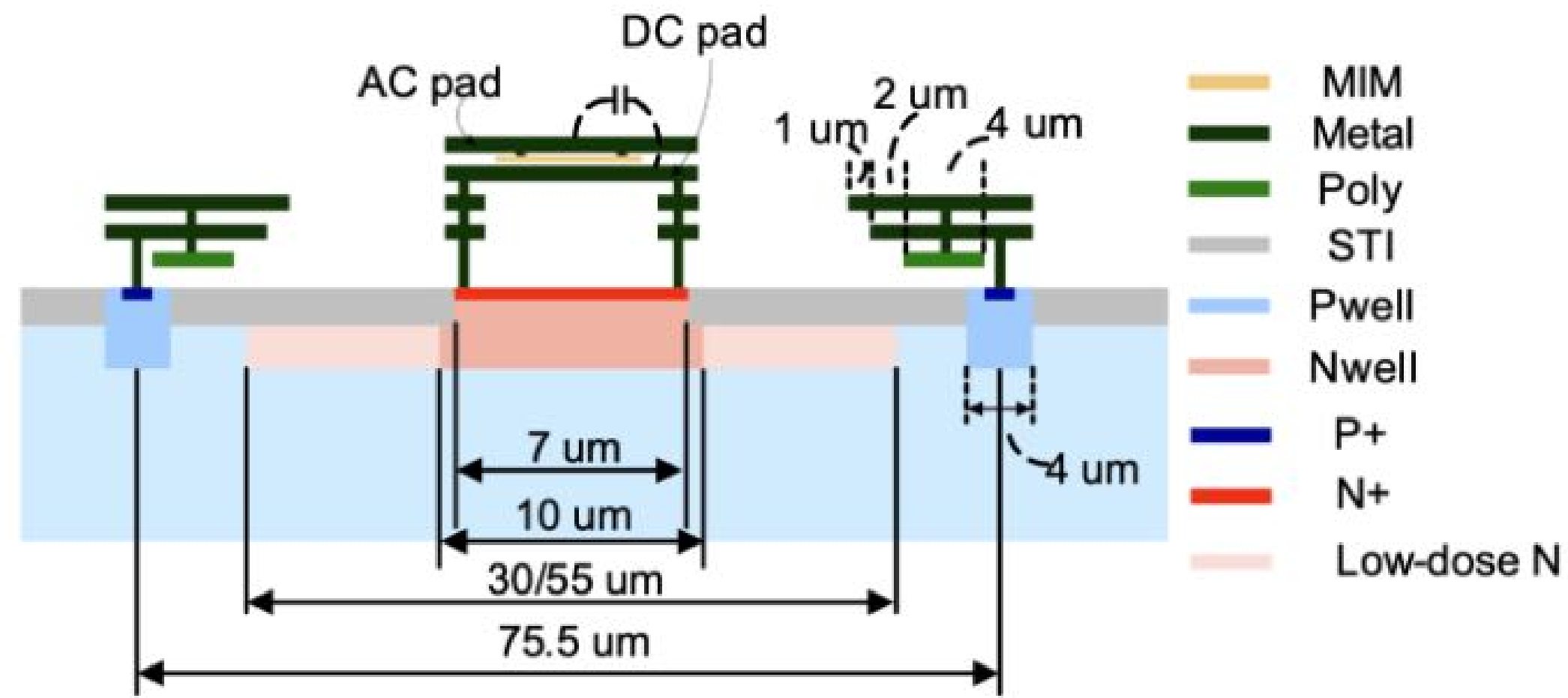
- Sensor thickness ~150 μm
- Strip pitch = 75.5 μm

- Two different sensor flavours divided in left (wide) and right (thin) half of the sensor
- Each flavour has 40 strips
- Stitching reticles are ~1cm long

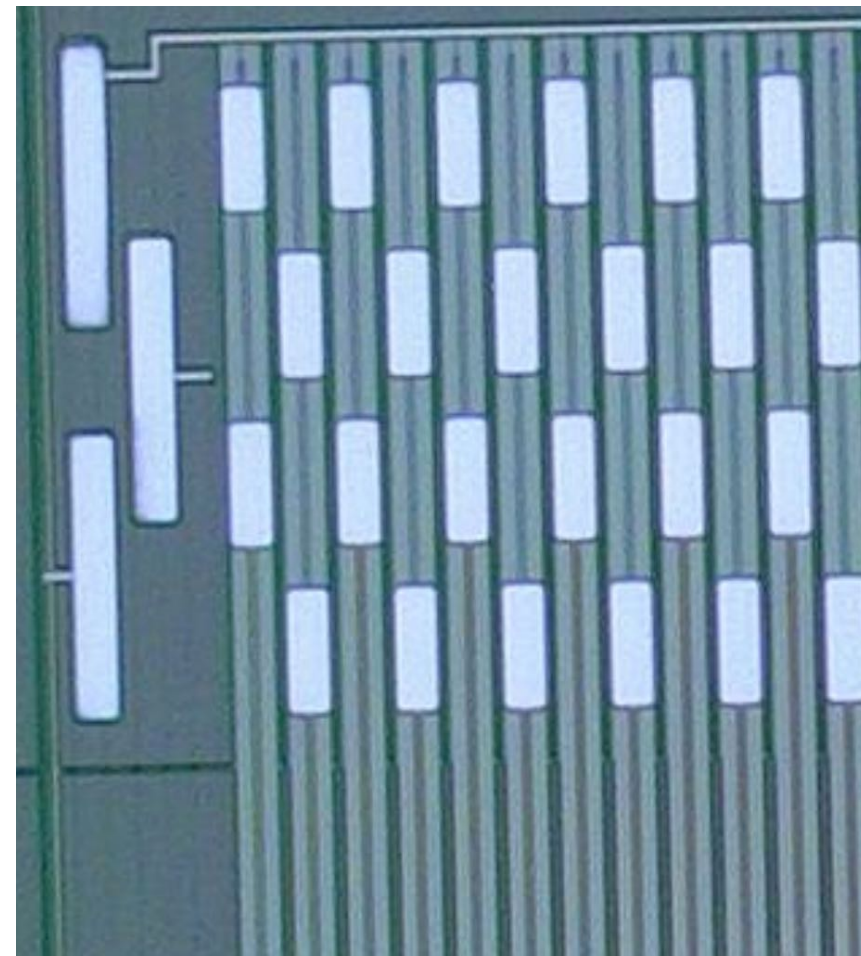
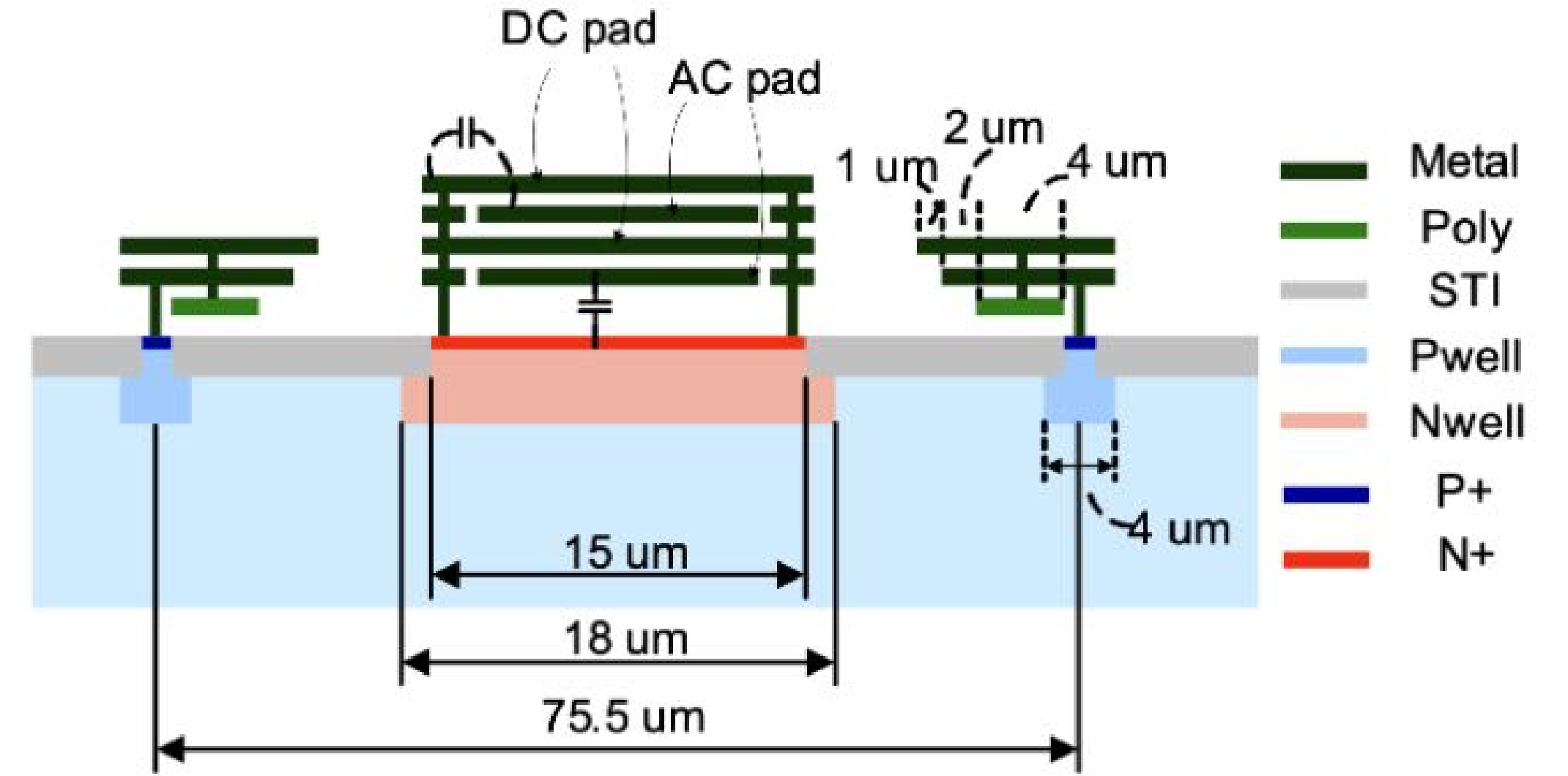


Sensor design

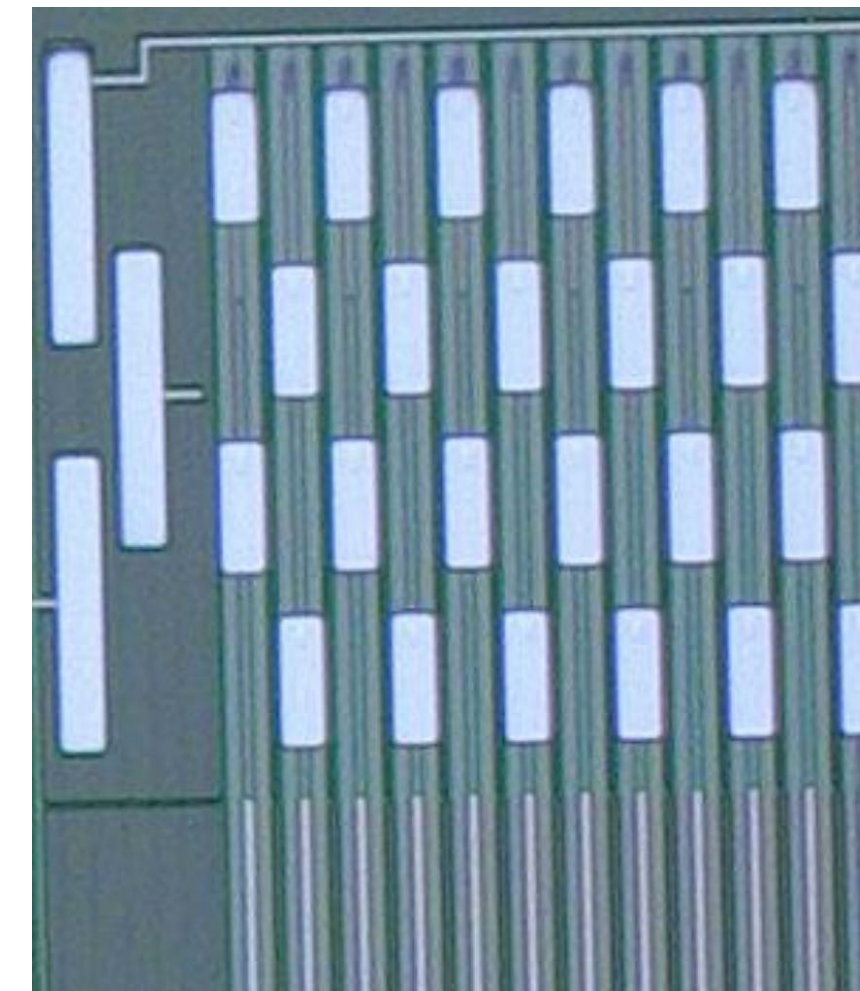
Wide implant



Thin implant



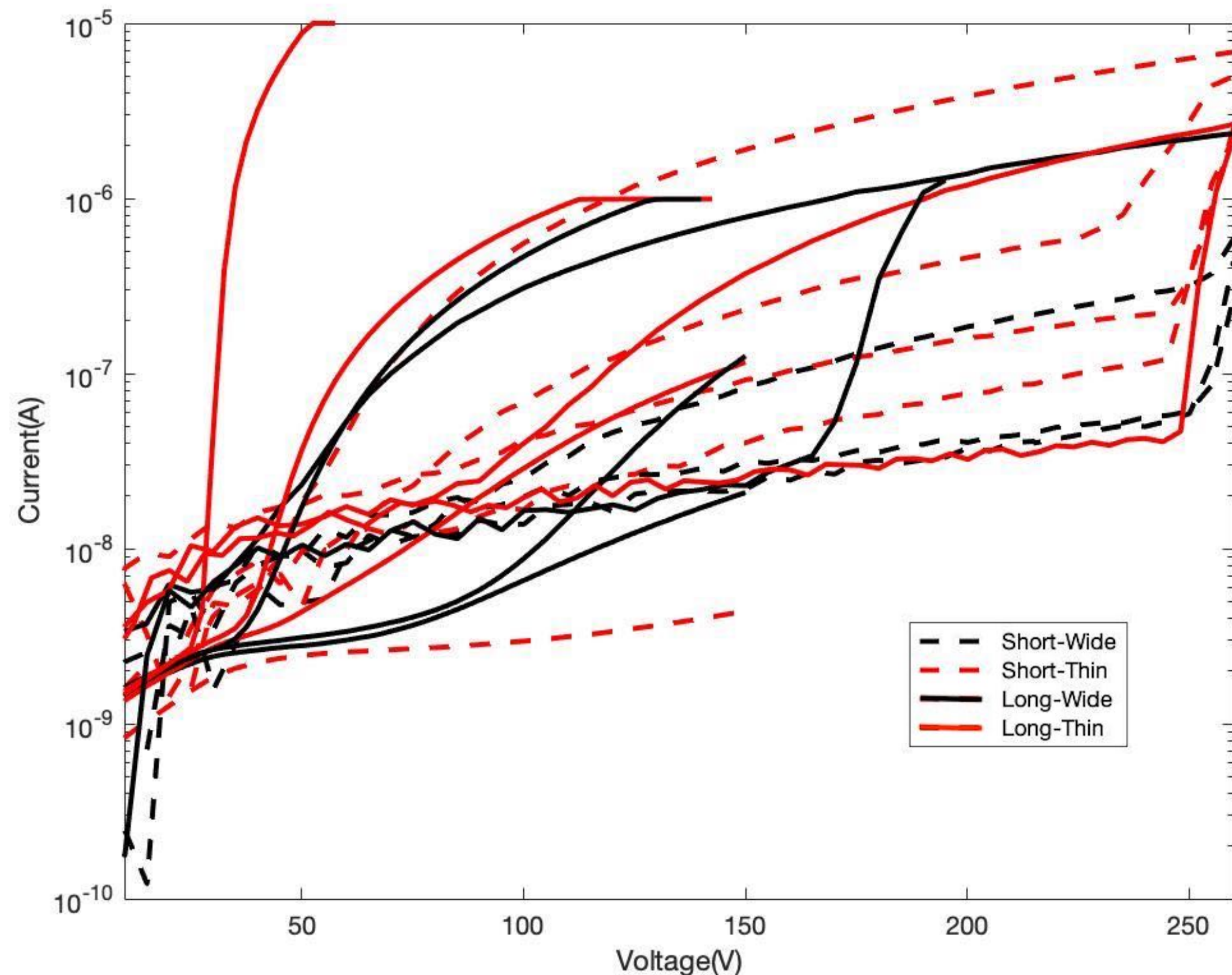
Wide implant has two different width for the low-dose N



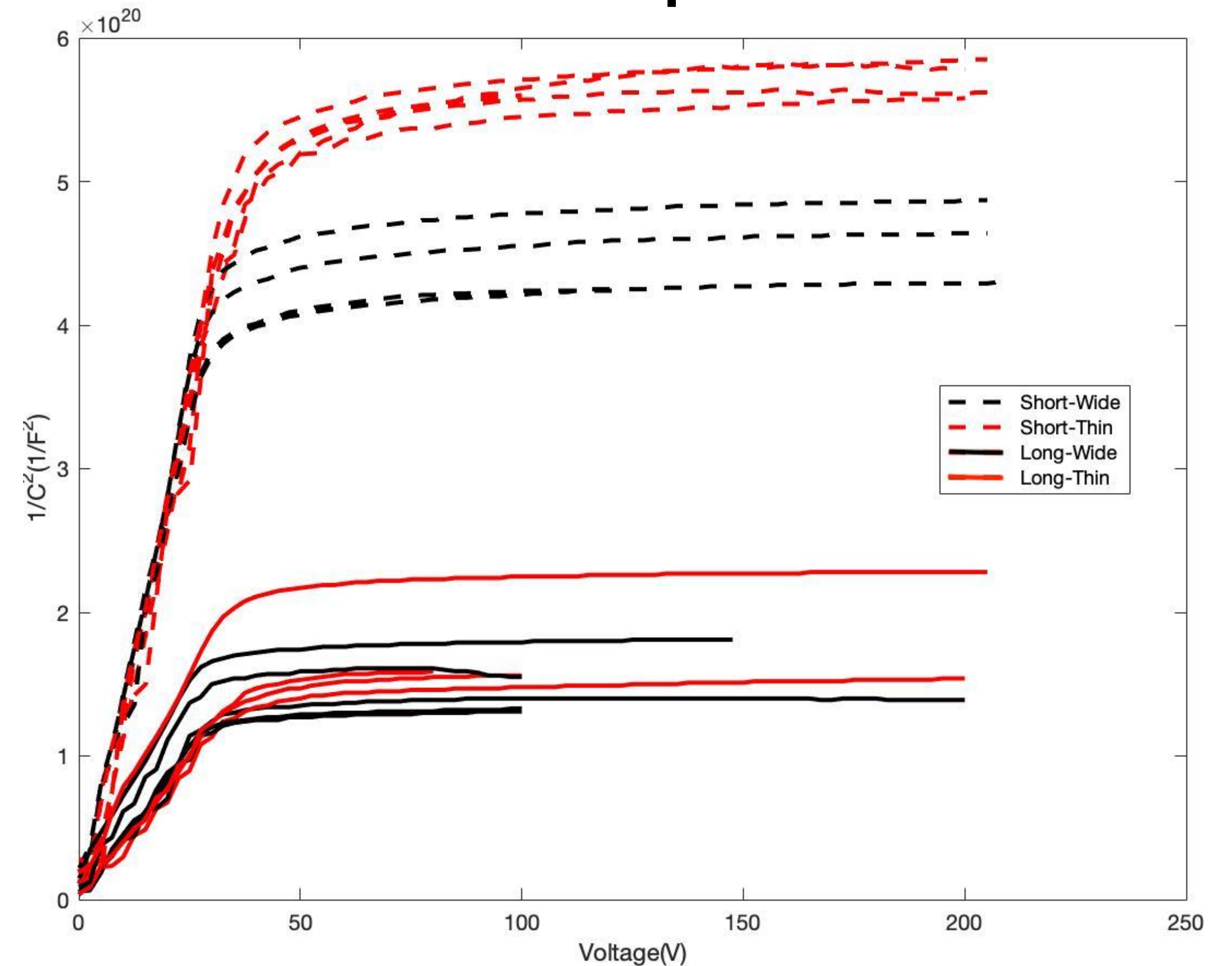
Electrical measurement

All measurements are performed at room temperature

IV plot



CV plot

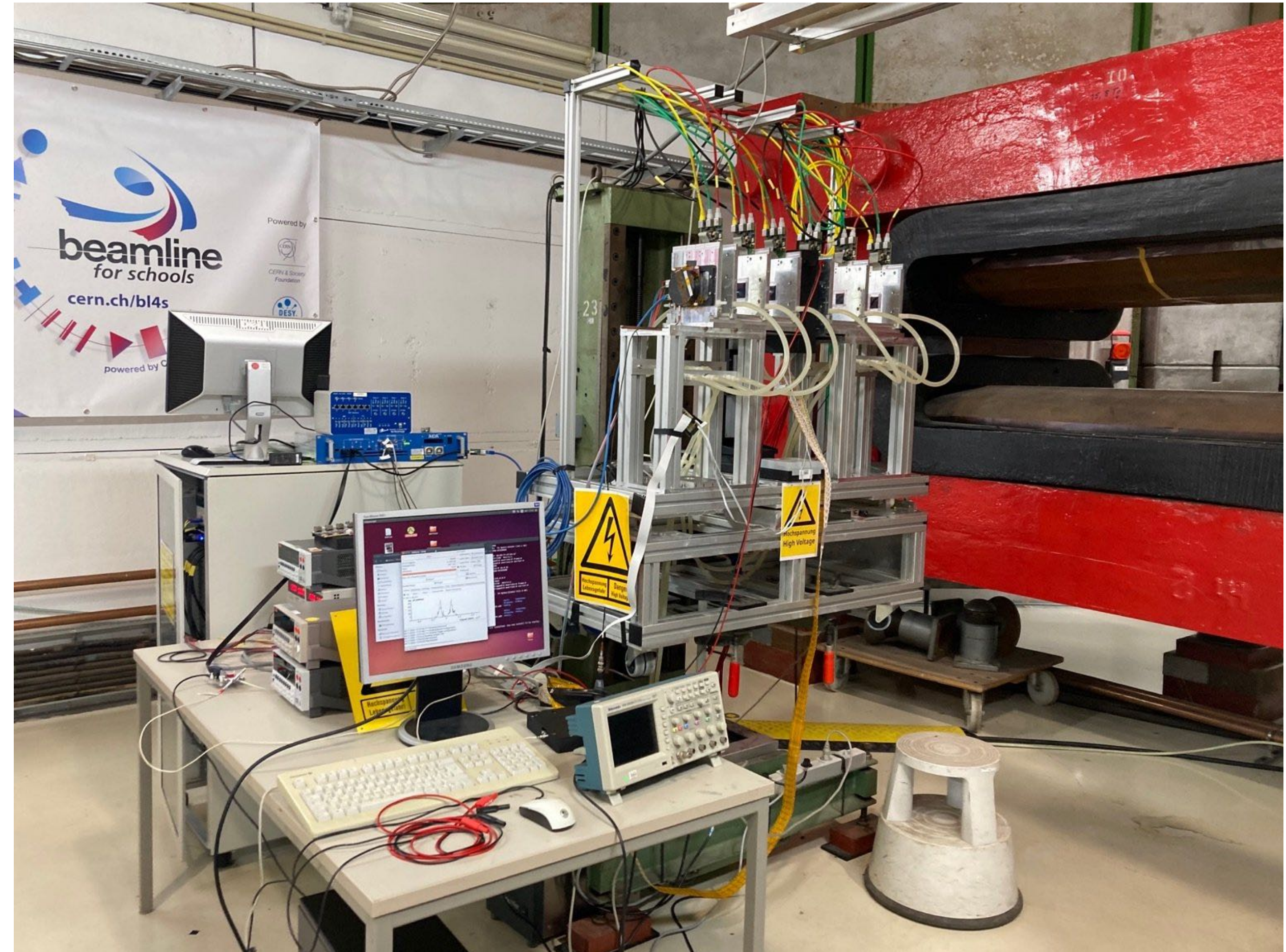


- For some of the sensor breakdown voltage is around 250V
- Some sensors show early breakdown -> bad backside process/implant (improved for next batch)

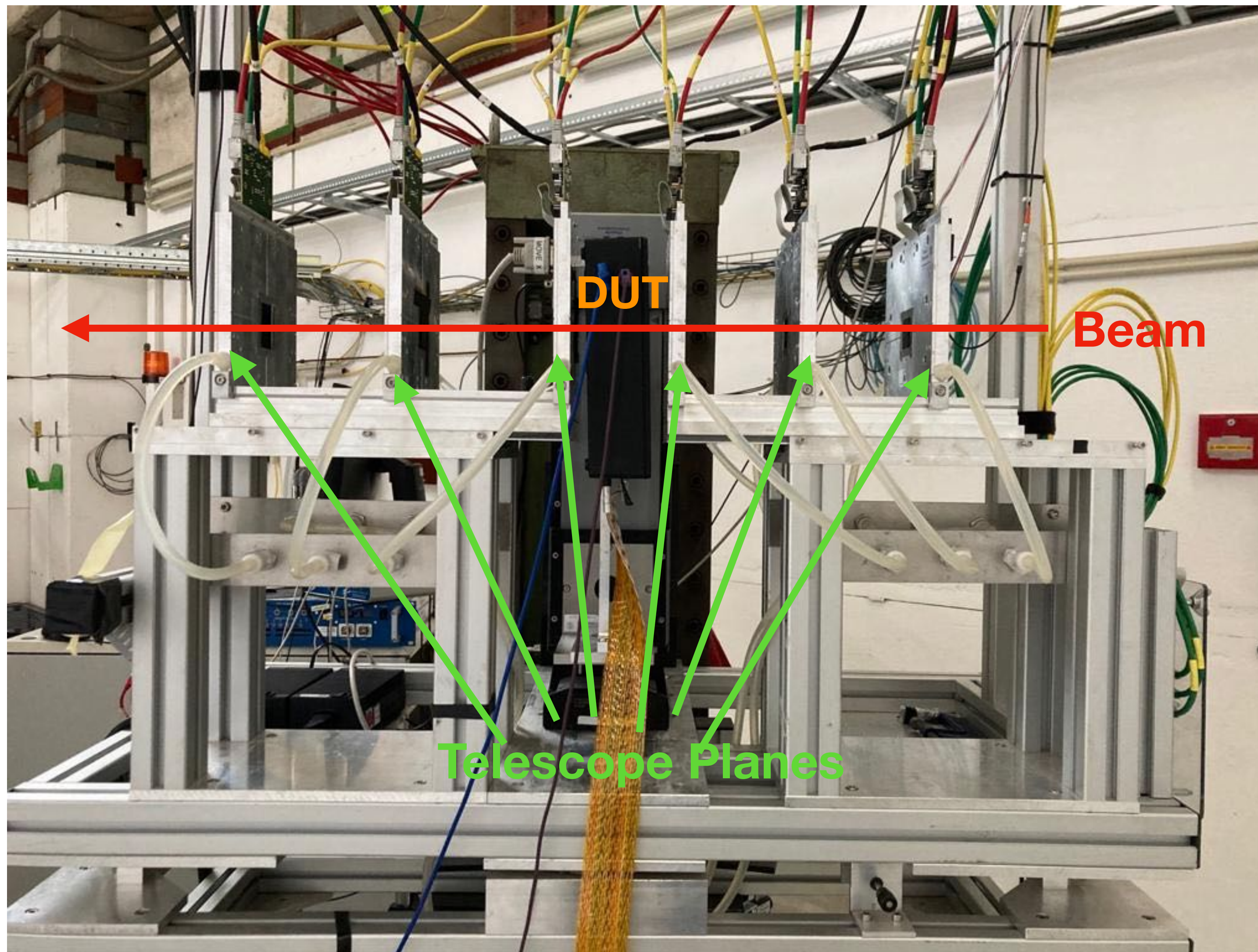
- The depletion voltage is in the range of 30-40V
- Depletion voltage for wide sensor < Depletion voltage for thin sensor

Goals for test beam

- Objectives
 - Sensor behaviour and signal formation with electrons
 - Study effects of stitching in the beam
 - Charge collection with different voltages
- Data taken at DESY II
 - Electron beam with beam energy 5 GeV
 - Using beam line 21 (DATURA telescope) with ALiBaVa system

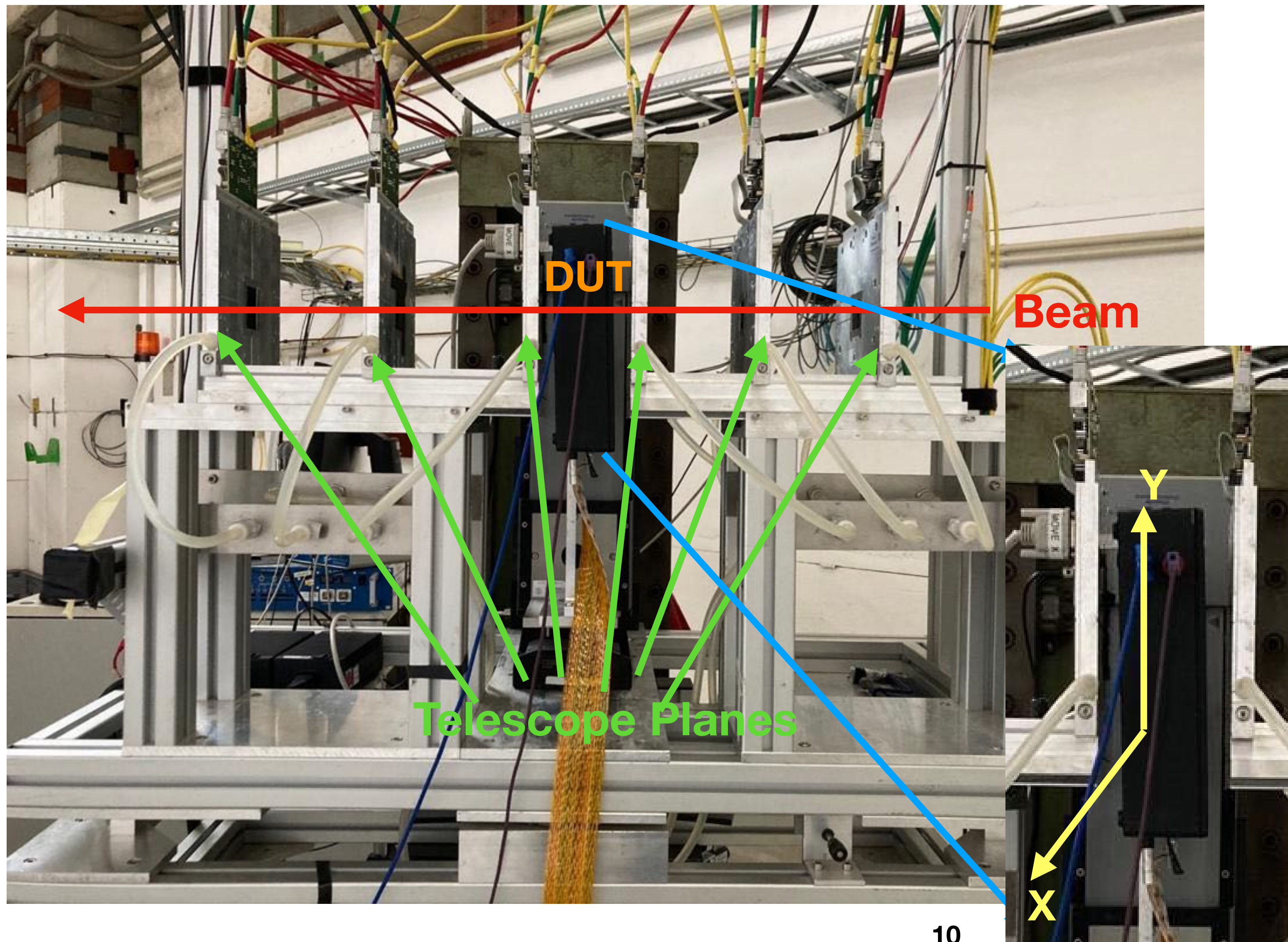


Setup for test beam



- Measurement for the long sensor is performed -> connected to the readout
- To study the effects of the stitching, sensor is scanned from top to bottom
- Temperature is monitored near the sensor

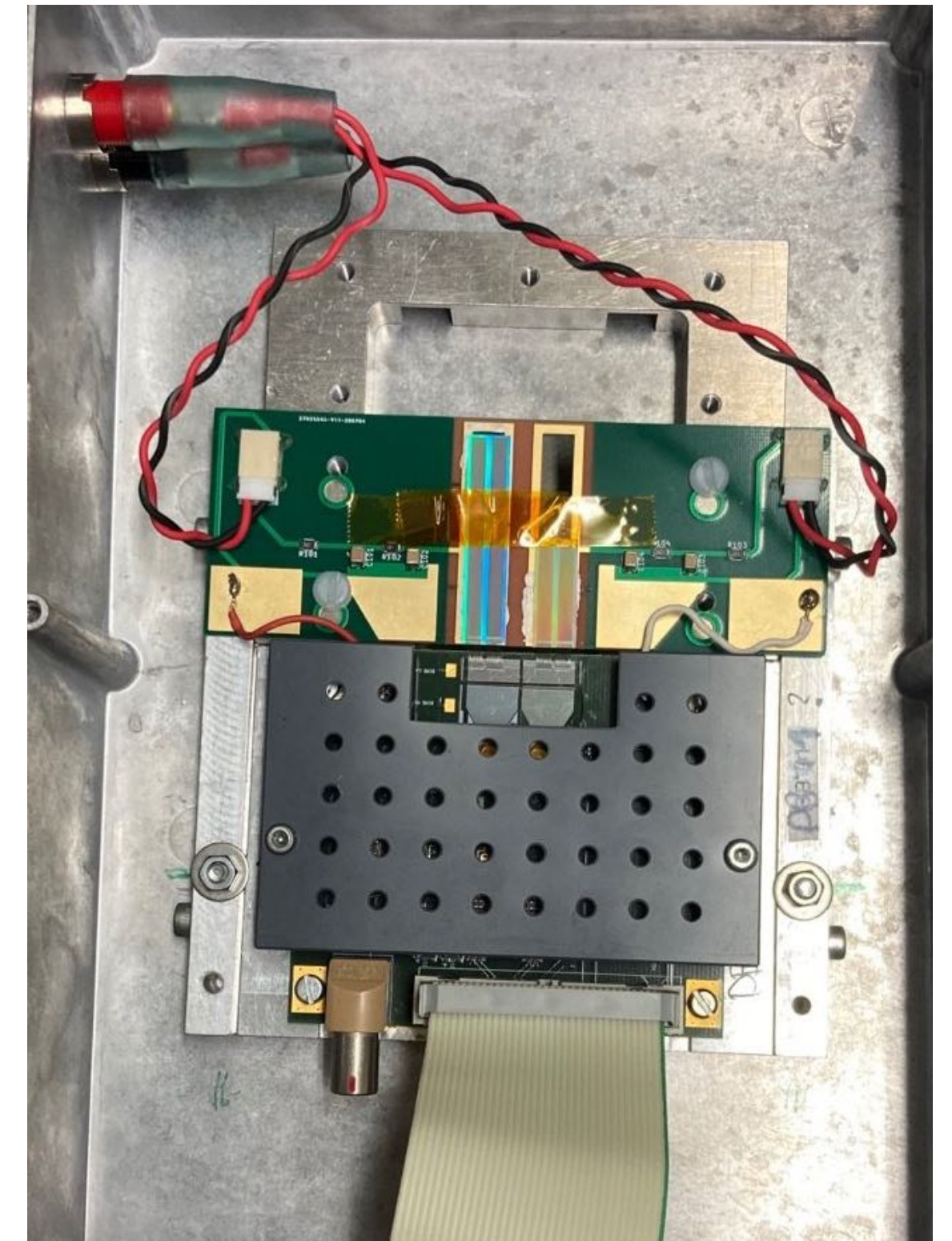
Setup for test beam



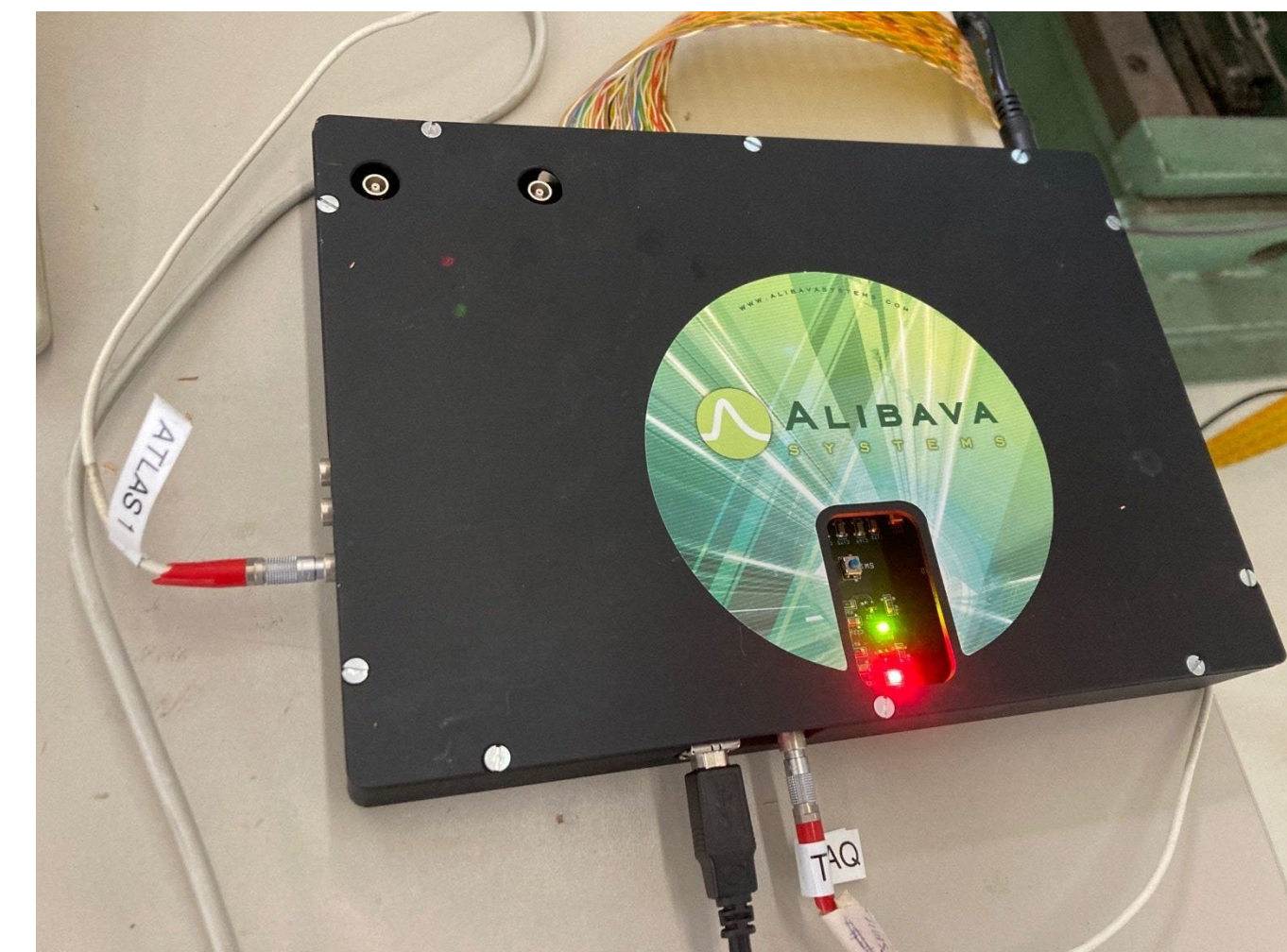
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ALiBaVa setup

- ALiBaVa is the readout system for silicon strip sensors particularly to study the charge collection with source or laser measurement
- The system uses an analogue readout chip and has two main components: daughter board and mother board
- Daughter board contains two beetle chip(used in LHCb) and is bonded to the silicon sensors under test
- Mother board process the analogue data that comes from daughter board

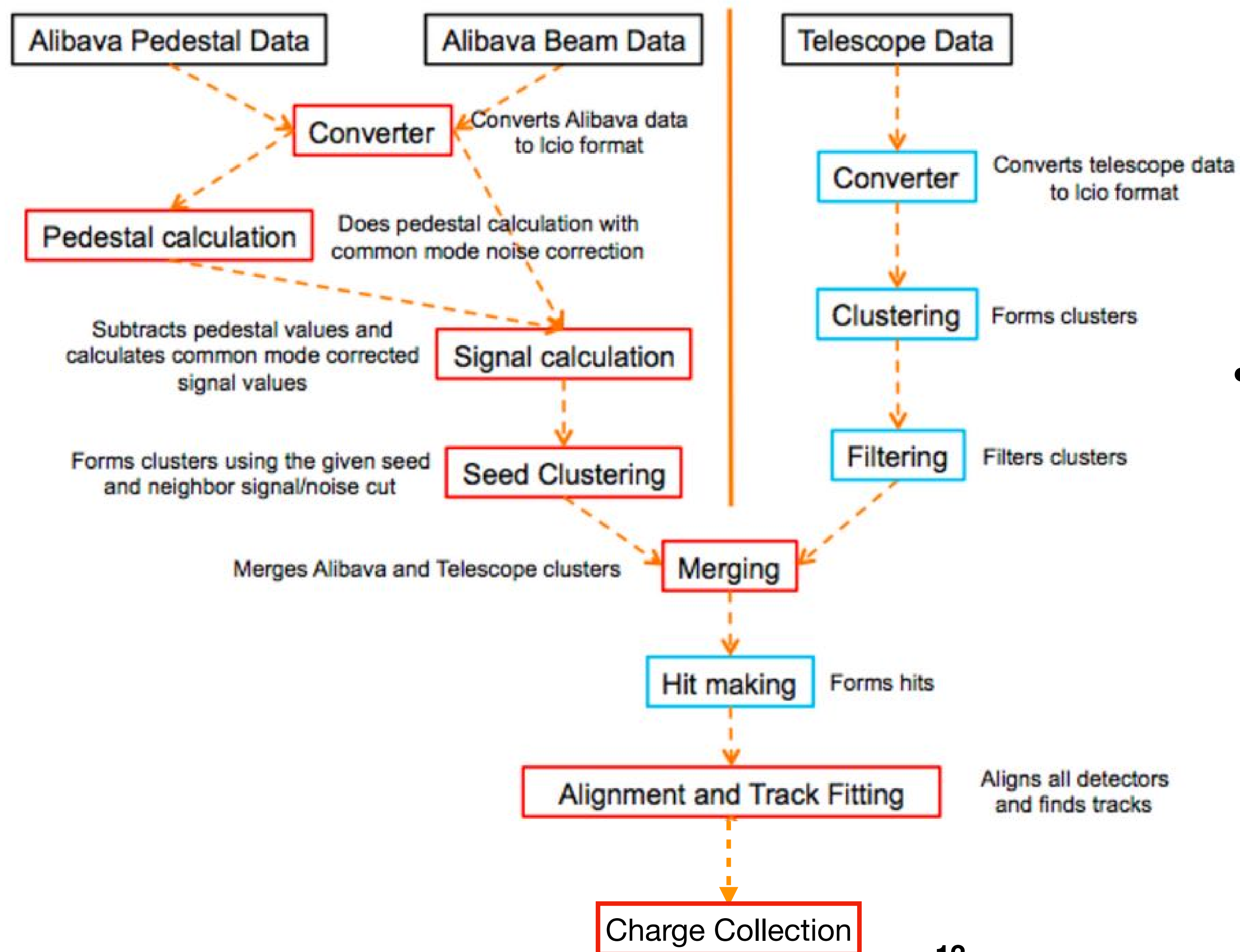


Sensor board with daughter board setup



Mother board

Analysis Strategy



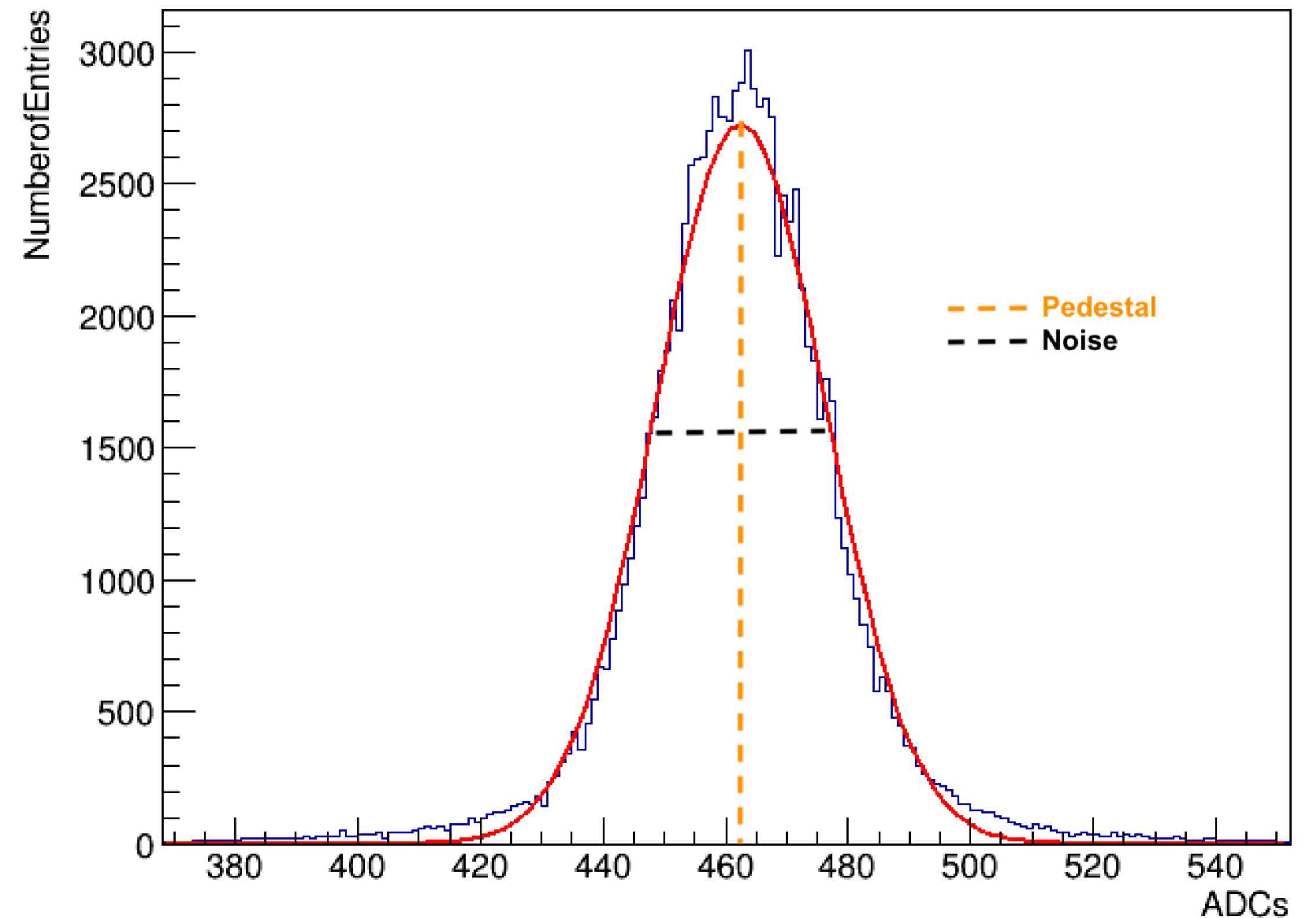
- Using EU Telescope for analysis

ALiBaVa data reconstruction

Pedestal Calculation

Pedestal and Noise Calculation

- Calculate base value and noise for each channel without any signal



ALiBaVa data reconstruction

Signal Calculation

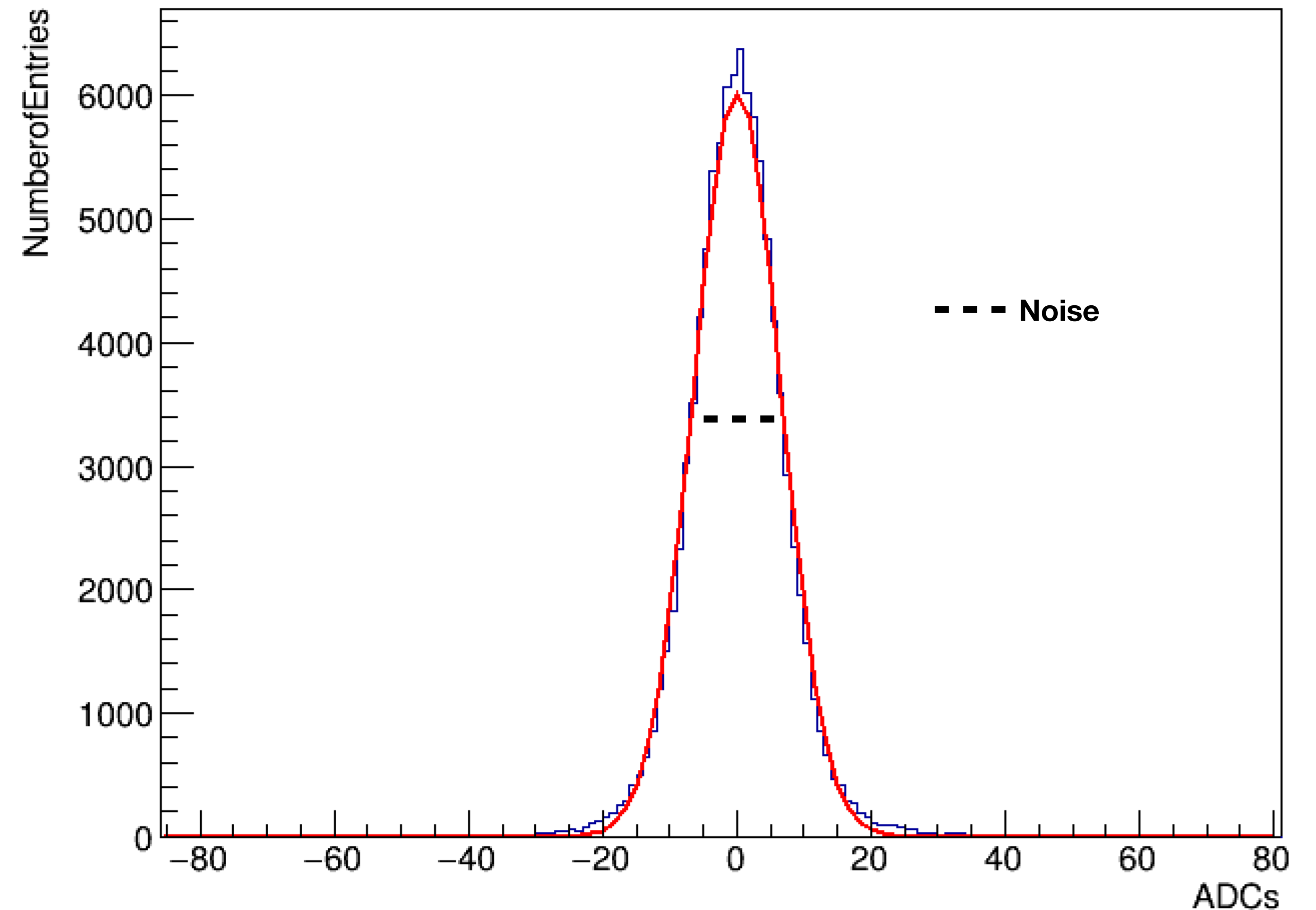
Data_chan_chip1_chan62

Pedestal and Noise Calculation

- Calculate base value and noise for each channel without any signal

Common Mode Correction

- Random shifts in voltage -> shifts in the channel base value
- Extra noise in the readout channel -> subtracted from the pedestal data

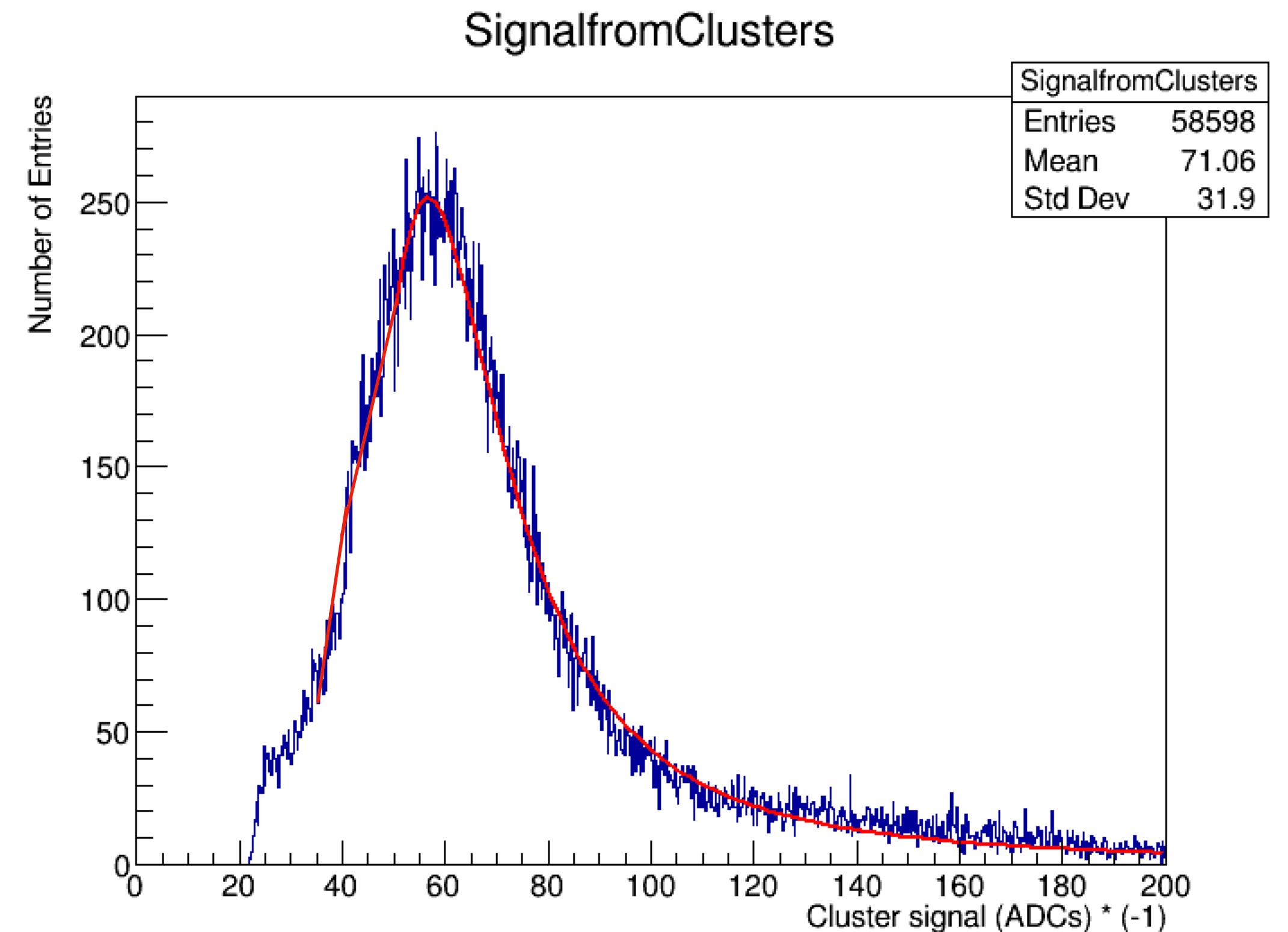
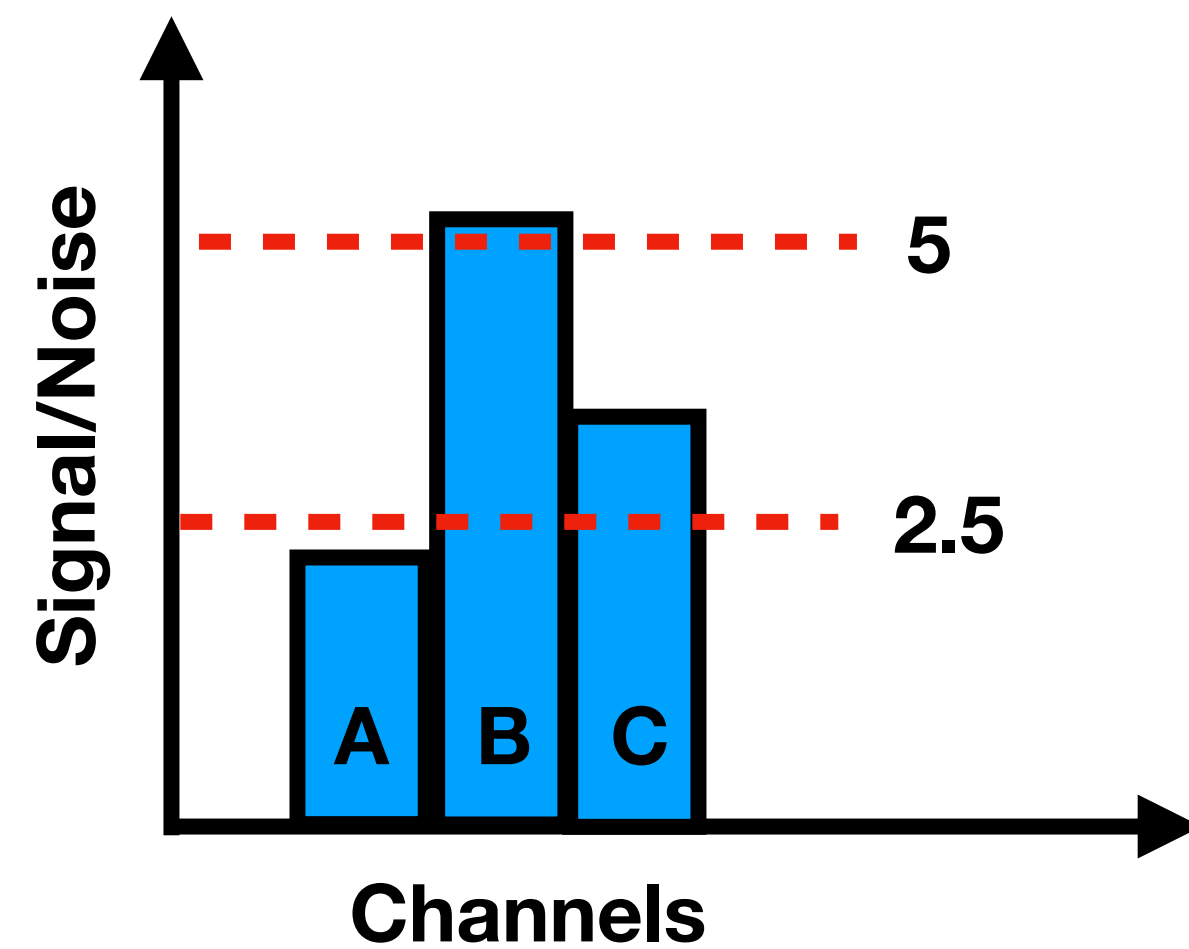


ALiBaVa data reconstruction

Seed Clustering

Clustering

- Seed : 5 x noise ; Neighbour: 2.5 x noise
- Neighbouring channels clustered with seed channel -> forms a cluster
- Maximum 5 channels in a cluster



ALiBaVa data reconstruction

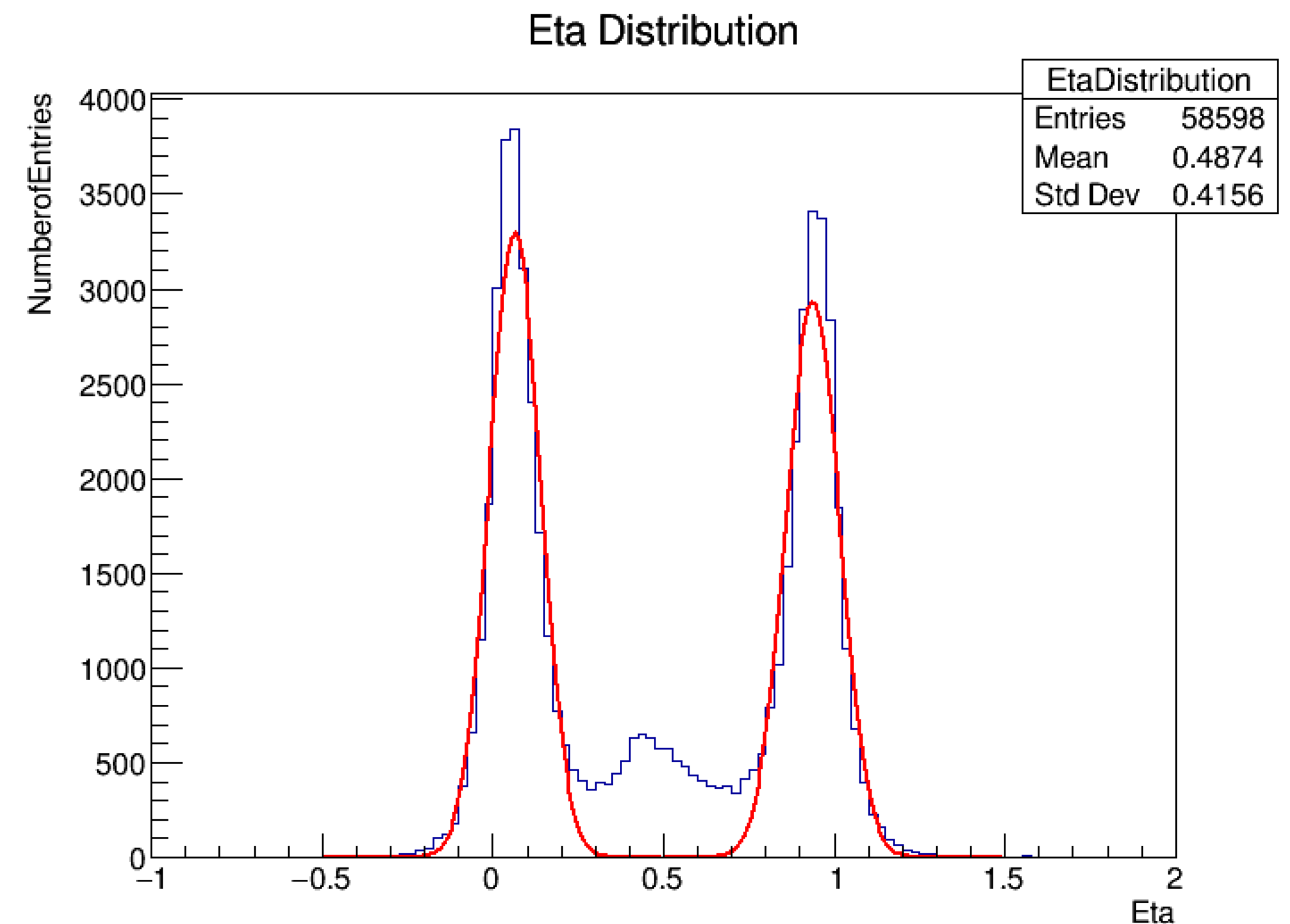
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Asymmetric Eta-Distribution

- Eta distribution shows the measure of charge division
- Left channel -> increased charge -> cross talk effect



ALiBaVa data reconstruction

Seed Clustering

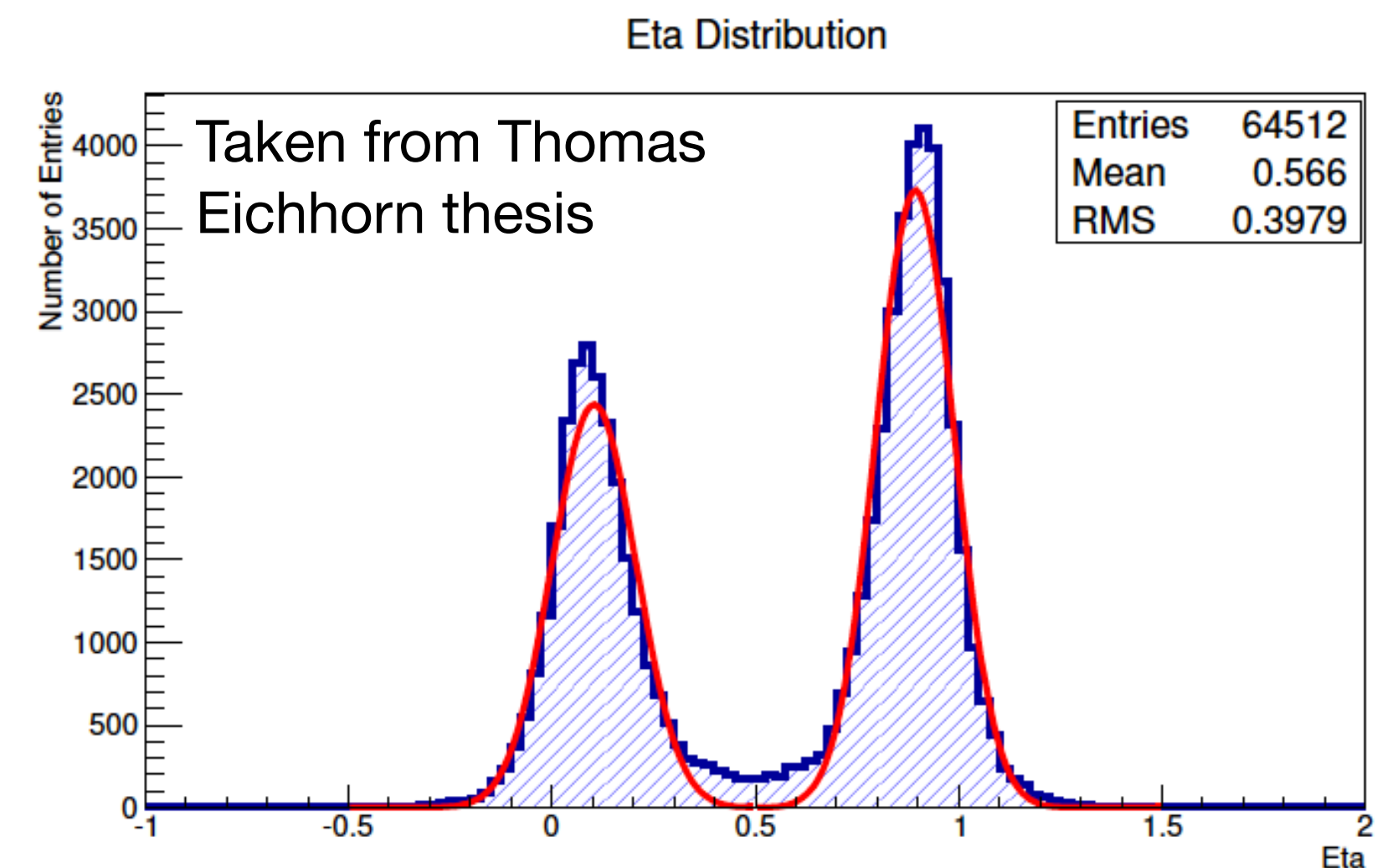
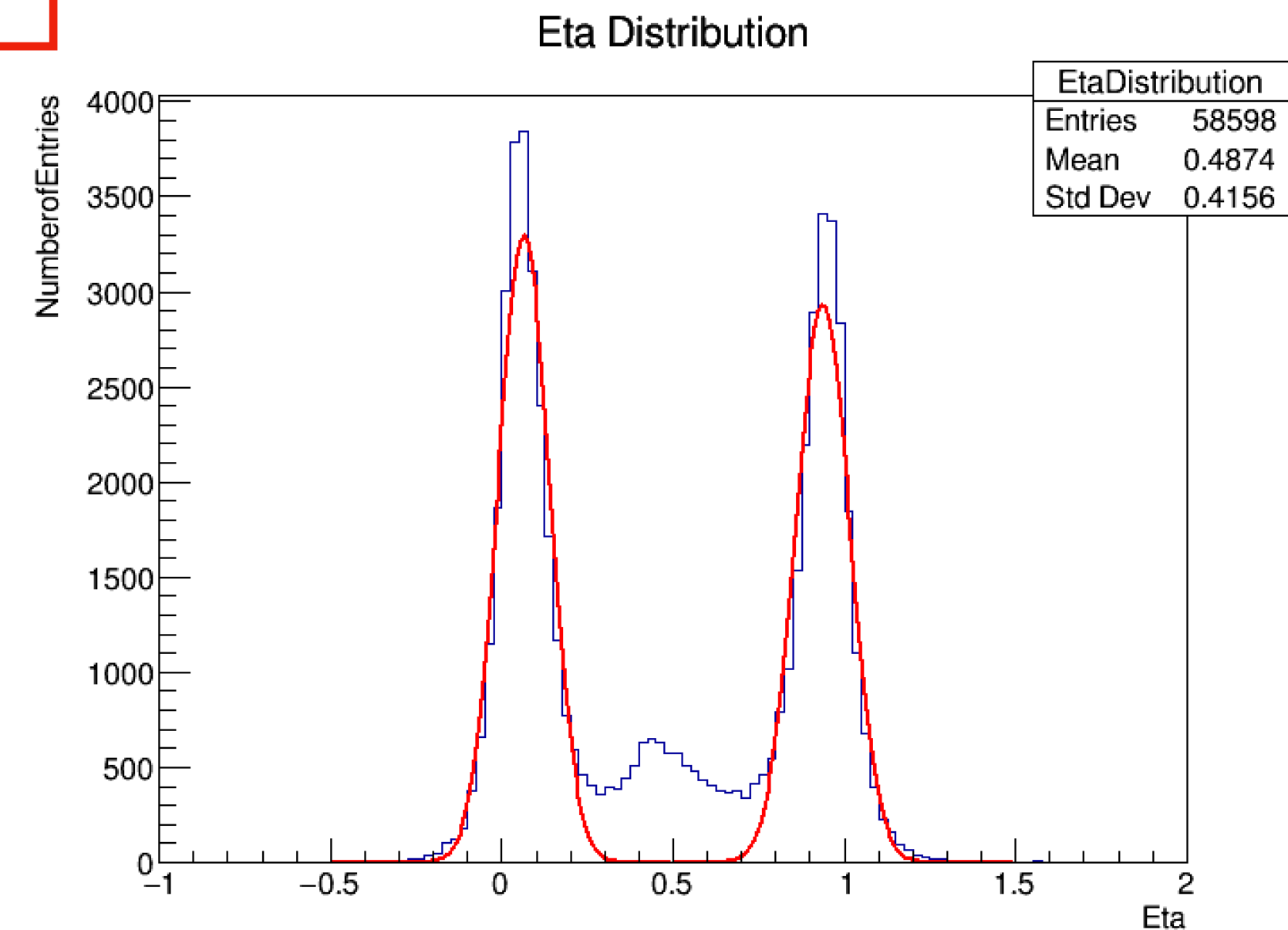
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Plot should be like this -> Charge sharing can be seen in previous plot around eta = 0.5



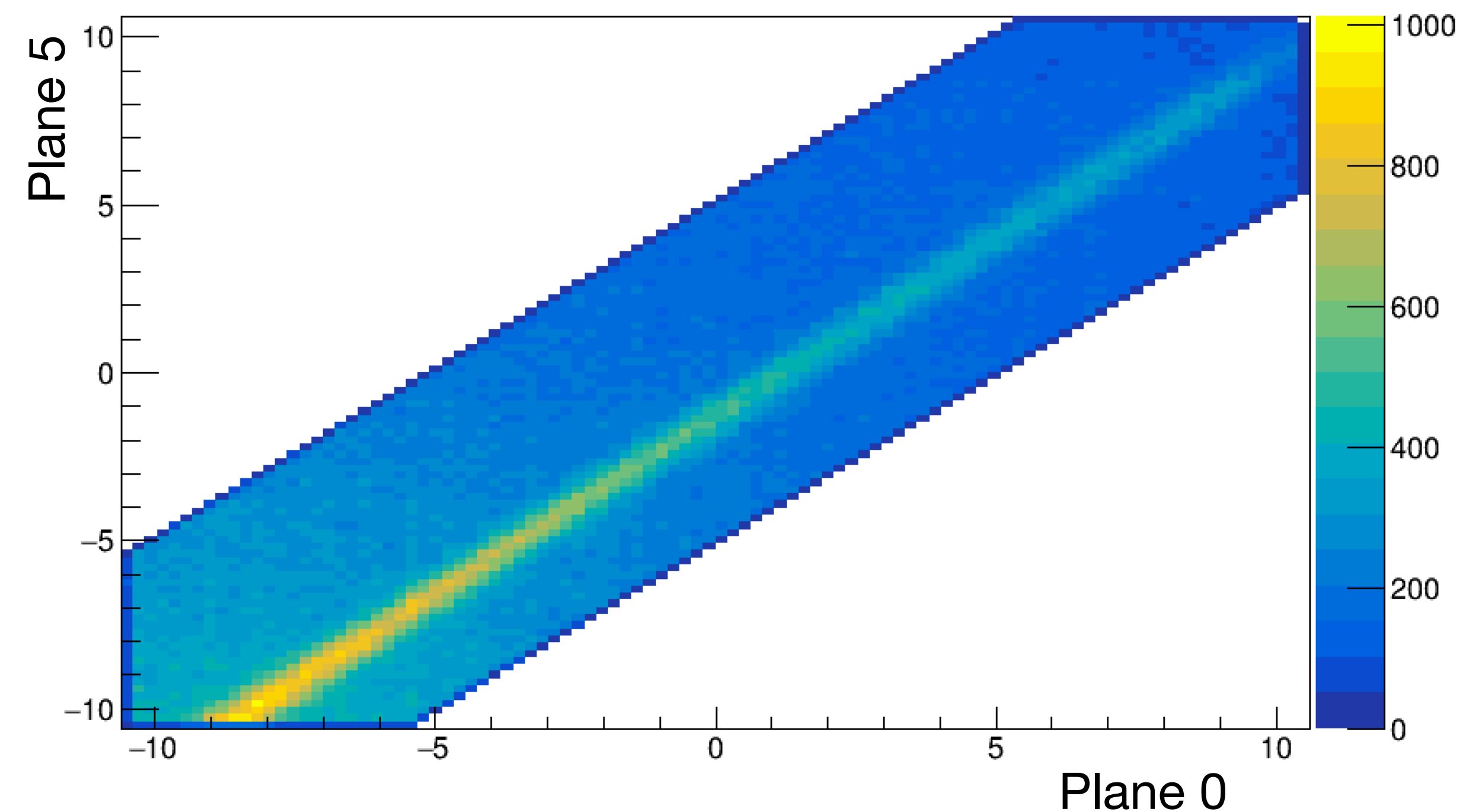
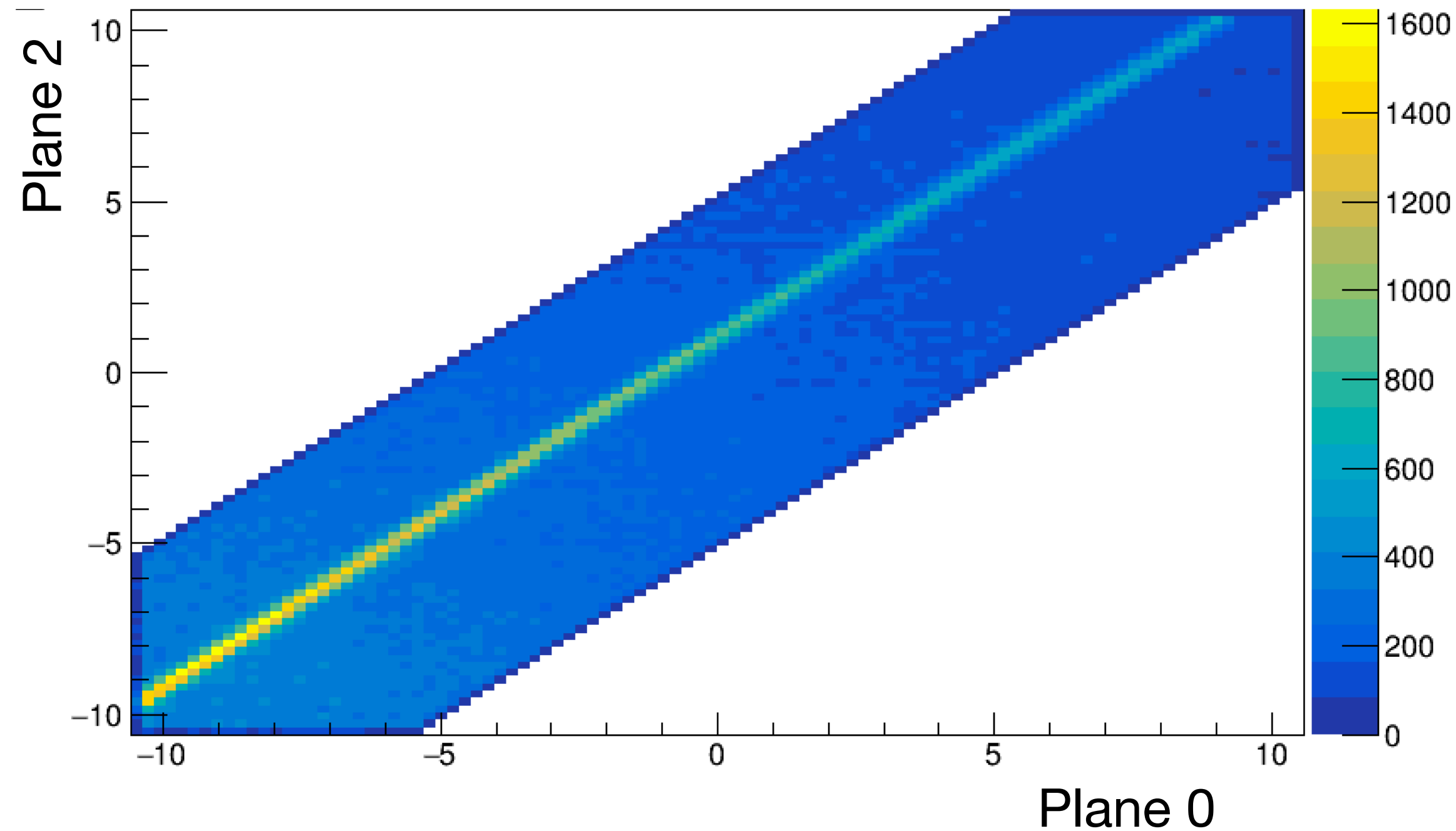
Telescope data reconstruction

Hitmaker

Without DUT

Hit correlation in X (d0->d2)

Hit correlation in X (d0->d5)



Correlation Plot

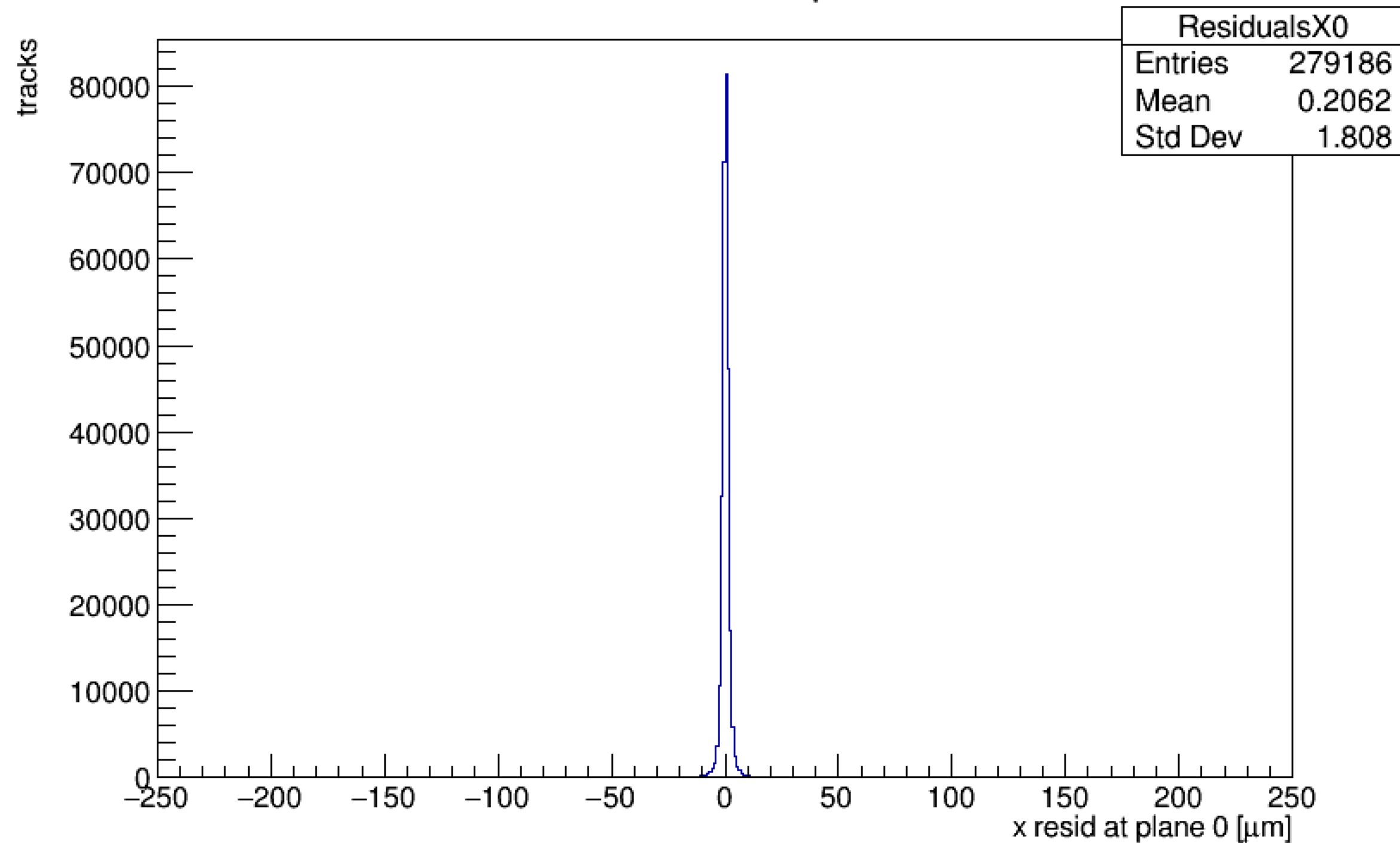
- Correlation between mimosa plane 1 and plane 3 is better than plane 1 and plane 6

Telescope data reconstruction

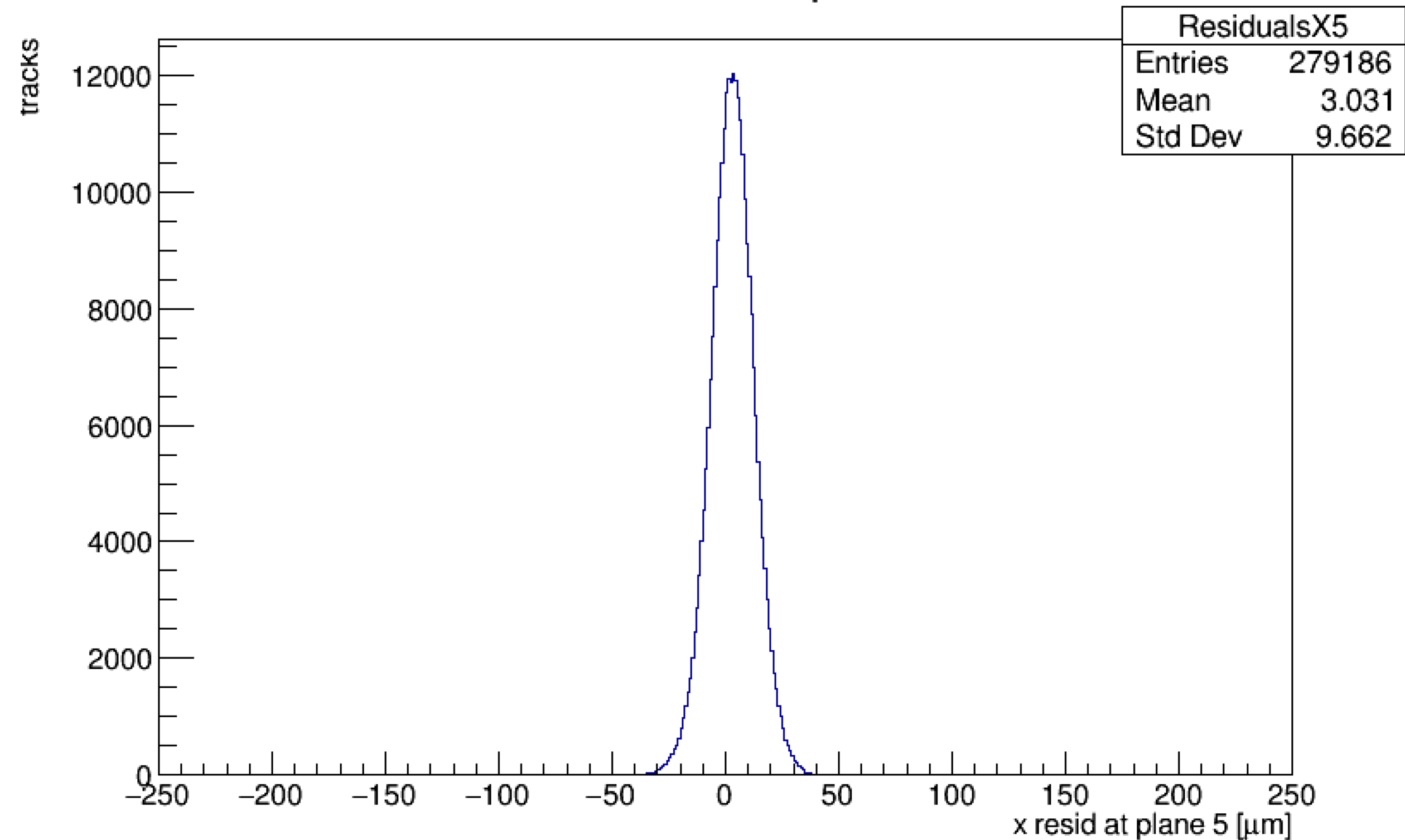
Alignment and Track Fitting

Without DUT

GBL residual at plane 0



GBL residual at plane 5



Residual Plot

- Residual -> distance between hit and fitted track extrapolation
- First iteration of residual values shows reasonable value

Summary

- Performed first test beam measurement for passive CMOS strip sensor
- Working on the analysis with EU Telescope
- Initial reconstruction and analysis shows data taken is reasonable

Outlook

- Continuing the analysis further
- New test beam and irradiation studies is also being planned
- New batch of sensor with back-side metallisation that improves the initial electrical measurement

The measurements leading to these results have been performed at the Test Beam Facility at DESY Hamburg (Germany), a member of the Helmholtz Association (HGF)

Thank You for Attention

Backup

ALiBaVa data reconstruction

Seed Clustering

Finite Impulse Response(FIR) filter

- Calculate the cross talk coefficient for left or right channel -> till 2 channels on both sides
- Calculate the amount of cross talk signal
- Subtract it from the measured signal

